

Description

Silicon Carbide (SiC) MOSFET use a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operating frequency, increased power density, reduced EMI, and reduced system size.

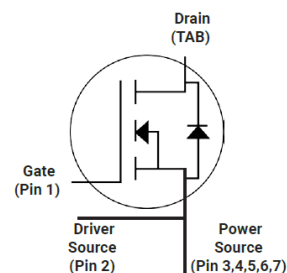
Features

- High Speed Switching with Low Capacitances
- High Blocking Voltage with Low RDS(on)
- Optimized package with separate driver source pin
- Easy to parallel and simple to drive
- ROHS Compliant, Halogen free



Application

- EV motor drive
- High Voltage DC/DC Converters
- Switch Mode Power Supplies
- Solar inverters
- EV charging



Ordering Information

Part Number	Marking	Package	Packaging
AMG60N1200MT7	AMG60N1200MT7	TO-263-7	Reel

Absolute Maximum Ratings(Tc=25℃)

Symbol	Parameter	Value	Unit
V _{DS}	Drain-Source Voltage	1200	V
I _D	Drain Current(continuous)at Tc=25℃	60	A
I _D	Drain Current(continuous)at Tc=100℃	48	A
I _{DM}	Drain Current (pulsed)	100	A
V _{GS}	Gate-Source Voltage	-10/+22	V
P _D	Power Dissipation T _C = 25℃	325	W
T _J , Tstg	Junction and Storage Temperature Range	-55 to +175	℃

Electrical Characteristics(T_J = 25℃ unless otherwise specified)
Typical Performance-Static

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV _{DS}	Drain-source Breakdown Voltage	I _D =250uA, V _{GS} =0V	1200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =1200V, V _{GS} =0V, T _J =25℃			100	uA
I _{GSS}	Gate-body Leakage Current	V _{DS} =0V ; V _{GS} =-10 to 20V			250	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =10mA	2	3	4	V
V _{GS(on)}	Recommended turn-on Voltage	Static		18		V
V _{GS(off)}	Recommended turn-off Voltage			-5		V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} =18V, I _D =20A		45	52	mΩ
		V _{GS} =18V, I _D =20A T _J =175℃		81		mΩ

Typical Performance-Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{DS}=1000V, f=100KHz,$ $V_{AC}=25mV$		2565		pF
C_{oss}	Output Capacitance			109		pF
C_{rss}	Reverse Transfer Capacitance			4		pF
g_{fs}	Transconductance	$V_{DS}=20V, I_D=20A$		24		S
E_{OSS}	C_{OSS} Stored Energy	$V_{DS}=1000V, f=100KHz$		63		μJ
E_{ON}	Turn-On Energy (Body Diode)	$V_{DS}=800V, V_{GS}=-5/20V,$ $I_D=30A, L=100\mu H$ $T_J=175^\circ C$		556		μJ
E_{OFF}	Turn-Off Energy (Body Diode)			93		μJ
Q_g	Total Gate Charge	$V_{DS}=800V, V_{GS}=-5V/20V,$ $I_D = 20A$		125		nC
Q_{gs}	Gate-source Charge			32		nC
Q_{gd}	Gate-Drain Charge			33		nC
$R_{G(int)}$	Internal Gate Resistance	$f=1MHz, V_{AC}=25mV$		4.2		Ω
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=800V, V_{GS}=-5V/20V,$ $I_D = 20A, L=100 \mu H$ $R_{ext}=2.5\Omega$		13		ns
t_r	Rise Time			17		ns
$t_{d(off)}$	Turn-off Delay Time			23		ns
t_f	Fall Time			9		ns

Typical Performance-Reverse Diode($T_J = 25^\circ C$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{FSD}	Forward Voltage	$V_{GS}=0V, I_F=20A, T_J=25^\circ C$		4.2	6	V
		$V_{GS}=0V, I_F=20A, T_J=175^\circ C$		3.5	6	V
I_S	Continuous Diode Forward Current	$V_{GS}=0V, T_C=25^\circ C$		55		A
t_{rr}	Reverse Recovery Time	$V_{GS}=-5V, I_F=20A,$ $V_R=800V, di/dt=900$ $A/\mu s, T_J=175^\circ C$		50		nS
Q_{rr}	Reverse Recovery Charge			712		nC
I_{rrm}	Peak Reverse Recovery Current			19		A

Thermal Characteristics

Symbol	Parameter	Value.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.46	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	40	$^\circ C/W$

The values are based on the junction-to case thermal impedance which is measured with the device mounted to a large heat sink assuming maximum junction temperature of $T_J(max)=175^\circ C$

Electrical Characteristics

Fig1. Output characteristics ($T_J = 25^\circ\text{C}$)

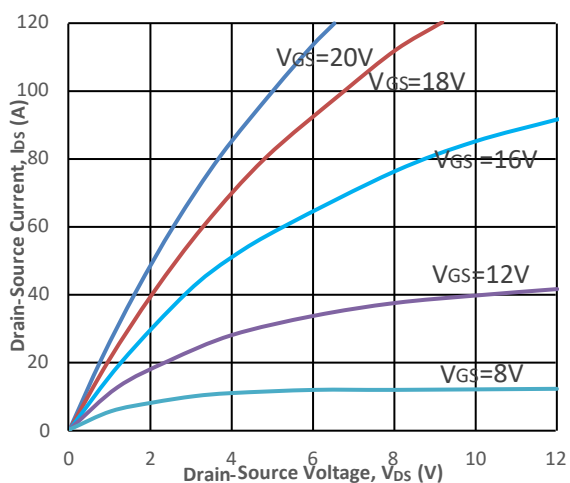


Fig2. Output characteristics ($T_J = 175^\circ\text{C}$)

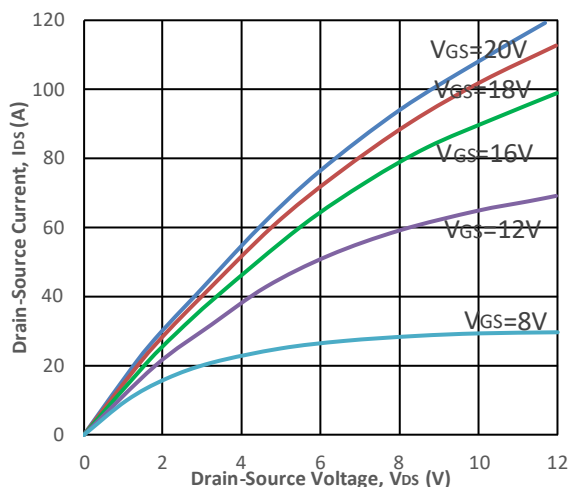


Fig3. Normalized On-Resistance vs. Temperature

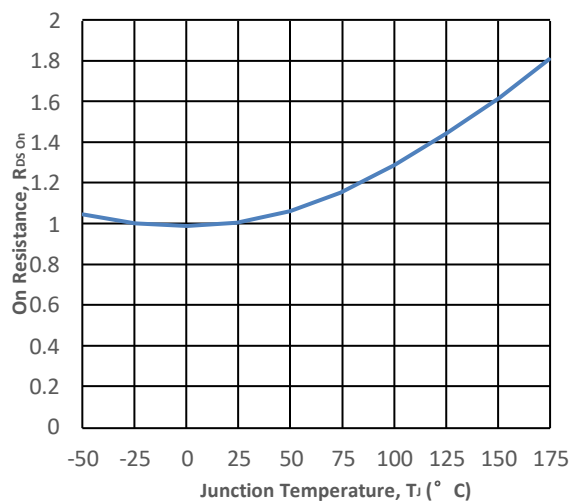


Fig4. On-Resistance vs. Temperature

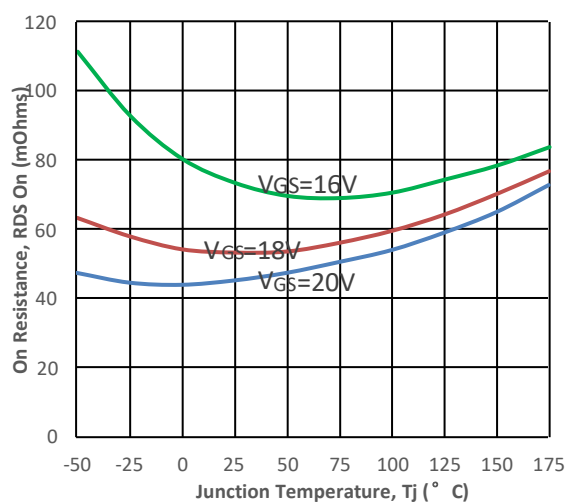


Fig5. Transfer Characteristic

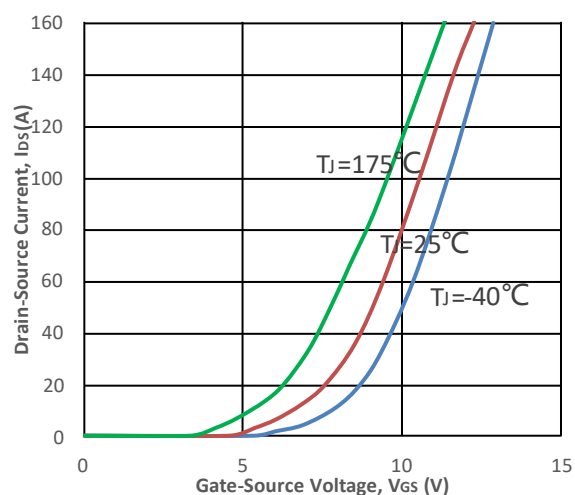


Fig6. Body Diode Characteristic at 25°C

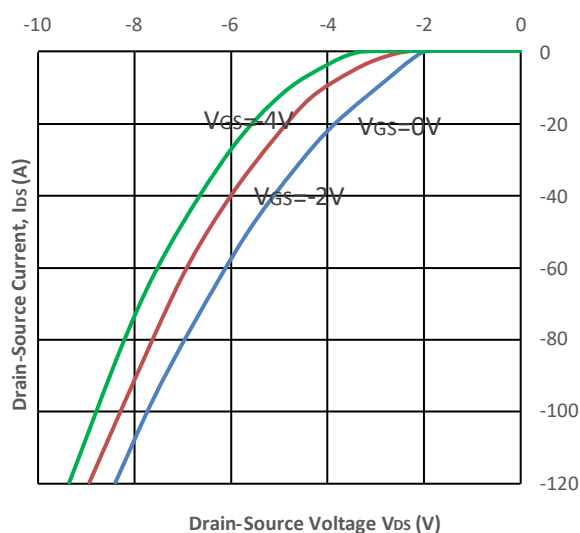


Fig7. Threshold Voltage vs. Temperature

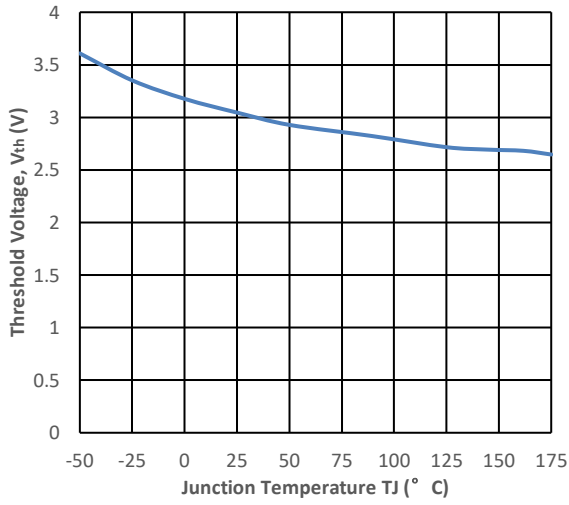


Fig8. Gate Charge Characteristics

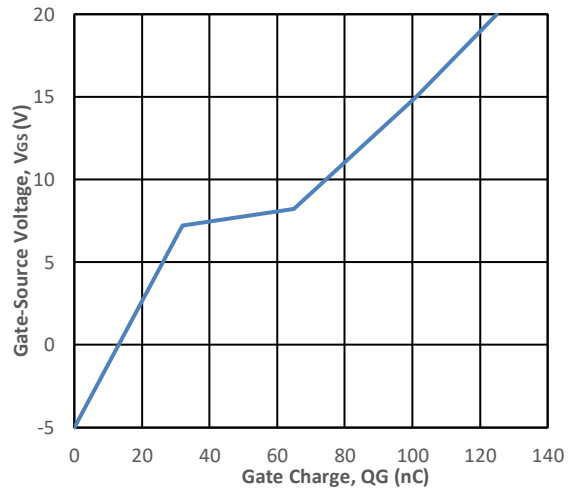


Fig9. 3rd Quadrant Characteristic at 25 °C

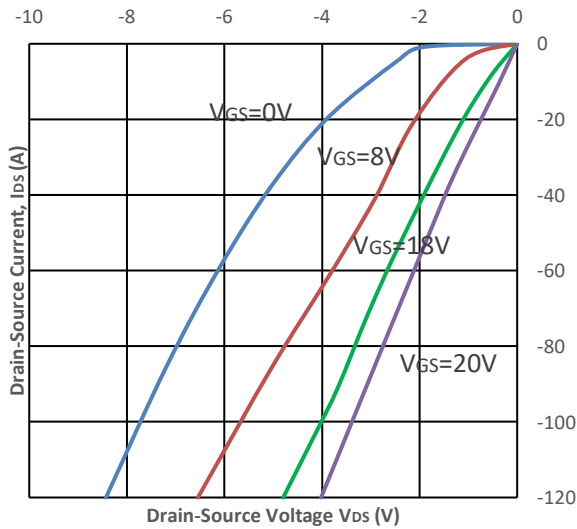


Fig10. Output Capacitor Stored Energy

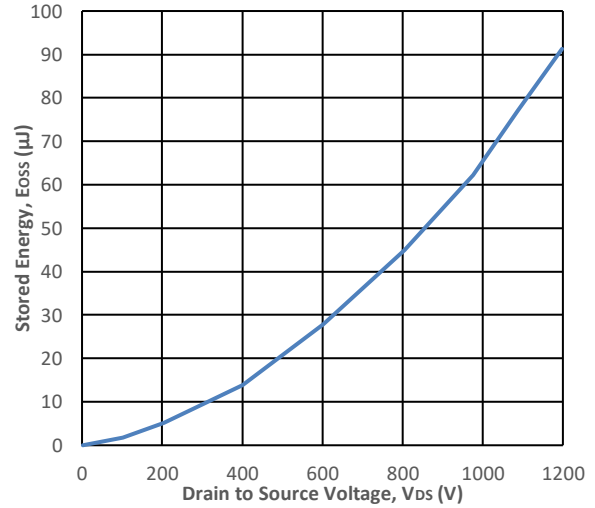


Fig11. Capacitances vs. Drain-Source

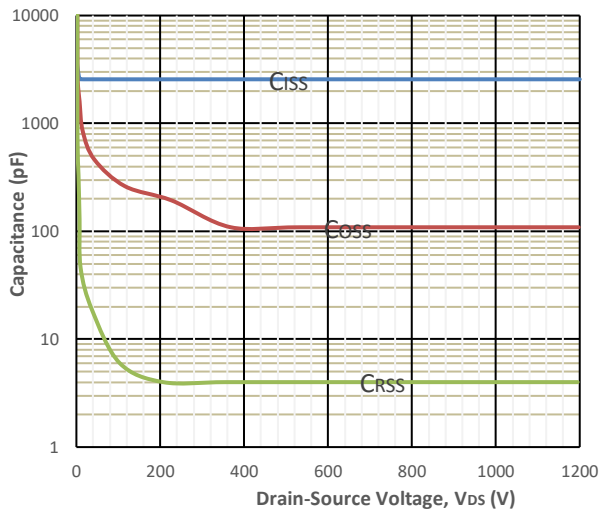


Fig12. Max Power Dissipation Derating Vs Tc

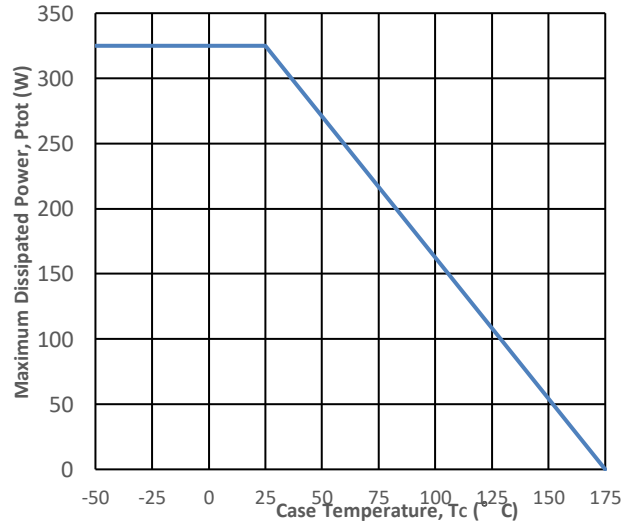


Fig13. Switching Energy vs. Drain Current

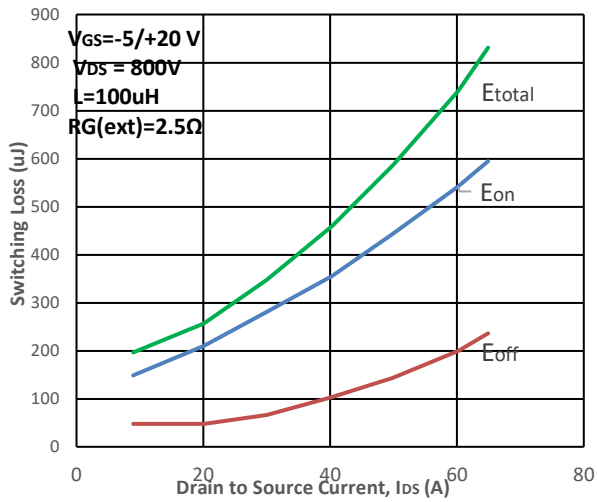


Fig14. Switching Energy vs. $R_{G(\text{ext})}$

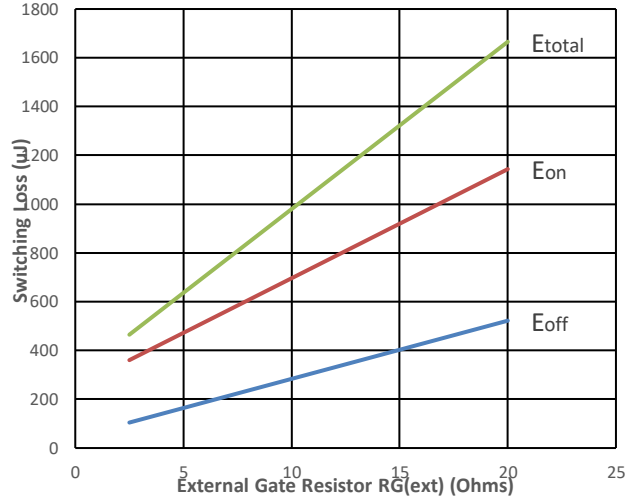


Fig15. Switching Energy vs. Temperature

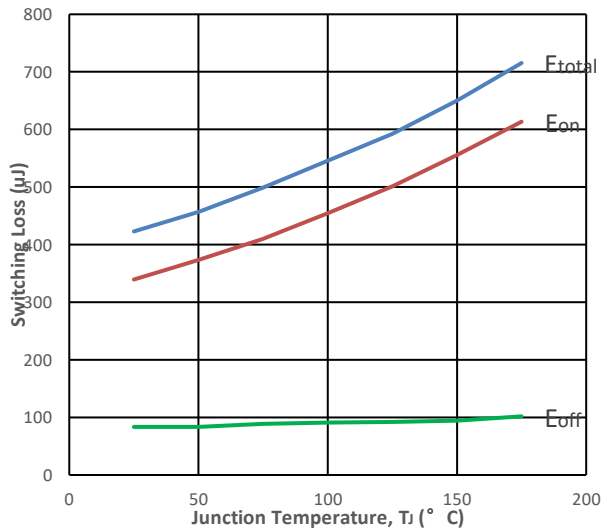


Fig16. Switching Times vs. $R_{G(\text{ext})}$

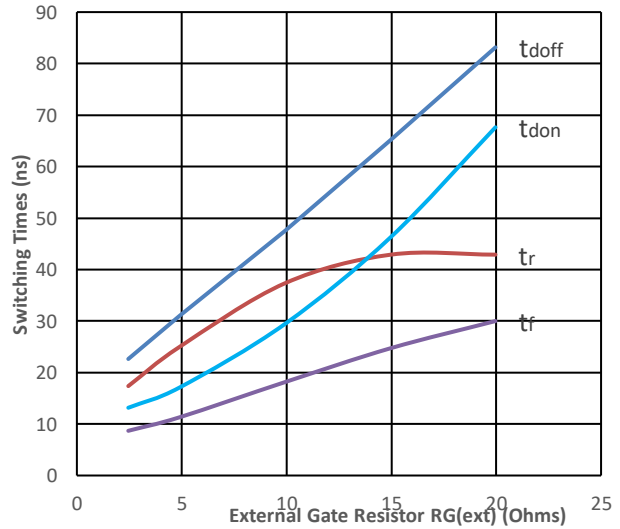


Fig17. Transient Thermal Impedance

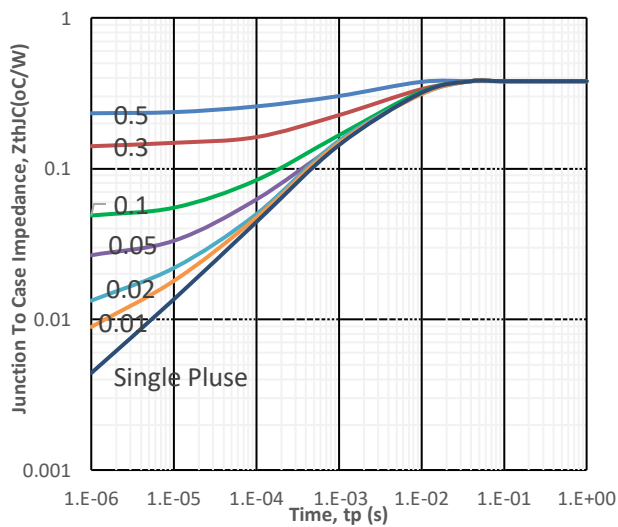
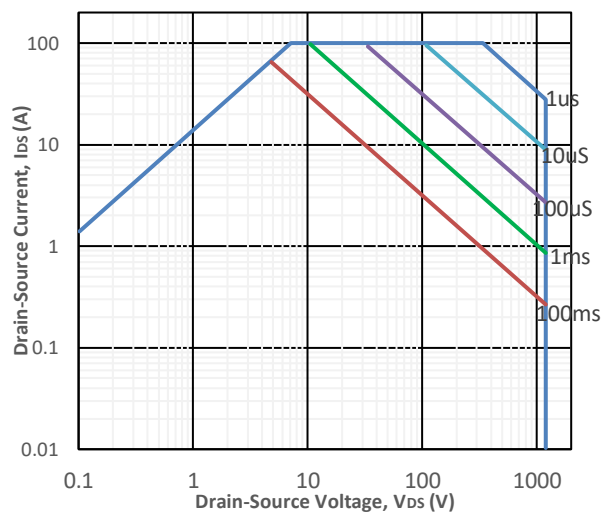
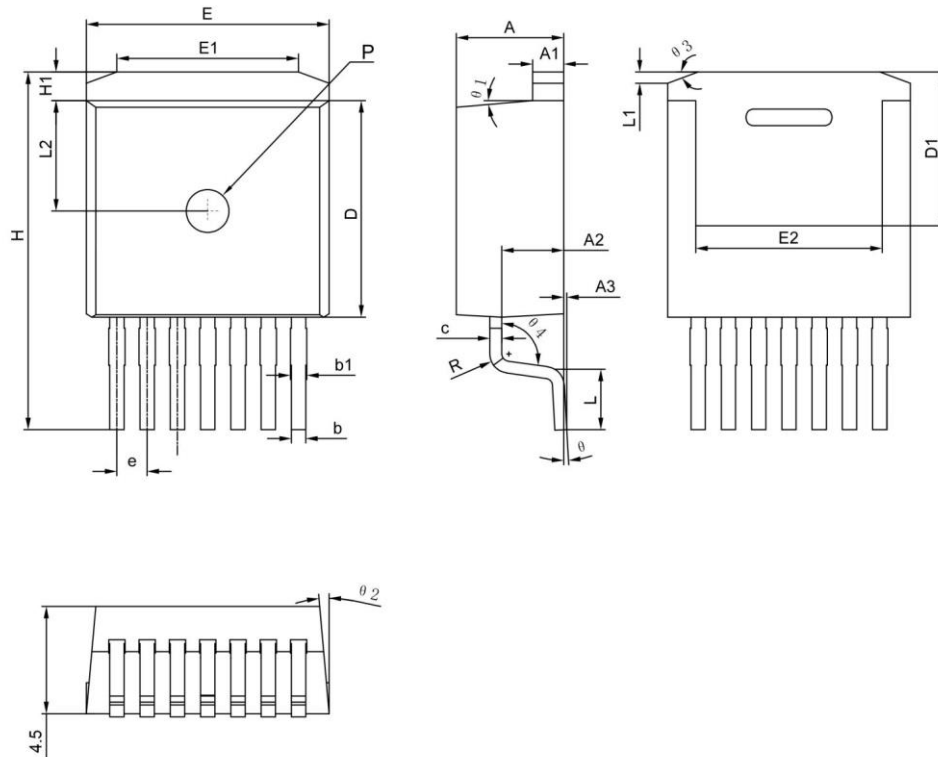


Fig18. Safe Operating Area



Package Drawing:

Dimensions (UNIT: mm)

SYMBOL	MIN	NOM	MAX
A	4.40	4.50	4.60
A1	1.25	1.30	1.40
A2	2.45	2.60	2.70
A3	0.05	0.13	0.20
b	0.50	0.60	0.70
b1	0.60	0.70	0.85
c	0.45	0.50	0.60
D	8.88	9.08	9.28
D1	6.25	6.45	6.65
E	9.18	10.18	10.28
E1	7.47	7.62	7.77
E2	7.67	7.82	7.97
e	1.17	1.27	1.37
H	14.80	15.00	15.20
H1	1.10	1.20	1.30
L	2.35	2.55	2.75
L1	0.27	0.47	0.67
L2	4.48	4.63	4.78
θ	0°	3°	5°
θ_1	3°	5°	7°
θ_2	3°	5°	7°
θ_3	15°	20°	25°
θ_4	93°	98°	100°
R	0.75	0.80	0.85
P	1.70	1.80	1.90